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Understanding Embedded - Microprocessors

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Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Ξ·XF

Obsolete
PowerPC e300c2
1 Core, 32-Bit
333MHz
Communications; QUICC Engine, Security; SEC 2.2
DDR, DDR2
No
-
10/100Mbps (3)
-
USB 2.0 (1)
1.8V, 2.5V, 3.3V
-40°C ~ 105°C (TA)
Cryptography
516-BBGA
516-PBGA (27x27)
https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8323ecvrafdca

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Electrical Characteristics

2.1.3 Output Driver Characteristics

Table 3 provides information on the characteristics of the output driver strengths. The values are preliminary estimates.

Driver Type	Output Impedance (Ω)	Supply Voltage
Local bus interface utilities signals	42	OV _{DD} = 3.3 V
PCI signals	25	
DDR1 signal	18	GV _{DD} = 2.5 V
DDR2 signal	18	GV _{DD} = 1.8 V
DUART, system control, I2C, SPI, JTAG	42	OV _{DD} = 3.3 V
GPIO signals	42	OV _{DD} = 3.3 V

Table 3. Output Drive Capability

2.1.4 Input Capacitance Specification

Table 4 describes the input capacitance for the CLKIN pin in the MPC8323E.

Table 4. Input Capacitance Specification

Parameter/Condition	Symbol	Min	Мах	Unit	Notes
Input capacitance for all pins except CLKIN	CI	6	8	pF	_
Input capacitance for CLKIN	C _{ICLKIN}	10		pF	1

Note:

1. The external clock generator should be able to drive 10 pF.

2.2 Power Sequencing

The device does not require the core supply voltage (V_{DD}) and IO supply voltages (GV_{DD}) and $OV_{DD})$ to be applied in any particular order. Note that during power ramp-up, before the power supplies are stable and if the I/O voltages are supplied before the core voltage, there might be a period of time that all input and output pins are actively driven and cause contention and excessive current. In order to avoid actively driving the I/O pins and to eliminate excessive current draw, apply the core voltage (V_{DD}) before the I/O voltage (GV_{DD}) and OV_{DD} and assert PORESET before the power supplies fully ramp up. In the case where the core voltage is applied first, the core voltage supply must rise to 90% of its nominal value before the I/O supplies reach 0.7 V; see Figure 3. Once both the power supplies (I/O voltage and core voltage) are stable, wait for a minimum of 32 clock cycles before negating PORESET.

Note that there is no specific power down sequence requirement for the device. I/O voltage supplies (GV_{DD}) and OV_{DD} do not have any ordering requirements with respect to one another.



CLKIN input current	$0 \ V \leq V_{IN} \leq OV_{DD}$	I _{IN}	_	±5	μA
PCI_SYNC_IN input current	$\begin{array}{c} 0 \ V \leq V_{IN} \leq 0.5 \ V \ or \\ OV_{DD} - 0.5 \ V \leq V_{IN} \leq OV_{DD} \end{array}$	I _{IN}	_	±5	μA
PCI_SYNC_IN input current	$0.5~V \leq V_{IN} \leq OV_{DD} - 0.5~V$	I _{IN}	—	±50	μA

4.2 AC Electrical Characteristics

The primary clock source for the MPC8323E can be one of two inputs, CLKIN or PCI_CLK, depending on whether the device is configured in PCI host or PCI agent mode. Table 8 provides the clock input (CLKIN/PCI_CLK) AC timing specifications for the MPC8323E.

Parameter/Condition	Symbol	Min	Typical	Мах	Unit	Notes
CLKIN/PCI_CLK frequency	f _{CLKIN}	25	—	66.67	MHz	1
CLKIN/PCI_CLK cycle time	t _{CLKIN}	15	—	—	ns	—
CLKIN rise and fall time	t _{KH} , t _{KL}	0.6	0.8	4	ns	2
PCI_CLK rise and fall time	t _{PCH} , t _{PCL}	0.6	0.8	1.2	ns	2
CLKIN/PCI_CLK duty cycle	t _{KHK} /t _{CLKIN}	40	—	60	%	3
CLKIN/PCI_CLK jitter		—	—	±150	ps	4, 5

Table 8. CLKIN AC Timing Specifications

Notes:

1. **Caution:** The system, core, security, and QUICC Engine block must not exceed their respective maximum or minimum operating frequencies.

2. Rise and fall times for CLKIN/PCI_CLK are measured at 0.4 and 2.7 V.

3. Timing is guaranteed by design and characterization.

4. This represents the total input jitter—short term and long term—and is guaranteed by design.

5. The CLKIN/PCI_CLK driver's closed loop jitter bandwidth should be < 500 kHz at -20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track CLKIN drivers with the specified jitter.

5 **RESET Initialization**

This section describes the AC electrical specifications for the reset initialization timing requirements of the MPC8323E. Table 9 provides the reset initialization AC timing specifications for the reset component(s).

Table 9. RESET Initialization Timir	g Specifications
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Parameter/Condition	Min	Max	Unit	Notes
Required assertion time of $\overrightarrow{\text{HRESET}}$ or $\overrightarrow{\text{SRESET}}$ (input) to activate reset flow	32	_	t _{PCI_SYNC_IN}	1
Required assertion time of $\overrightarrow{\text{PORESET}}$ with stable clock applied to CLKIN when the MPC8323E is in PCI host mode	32		t _{CLKIN}	2
Required assertion time of PORESET with stable clock applied to PCI_SYNC_IN when the MPC8323E is in PCI agent mode	32	_	^t PCI_SYNC_IN	1



DDR1 and DDR2 SDRAM

Table 11. Reset Signals DC Electrical Characteristics (continued)

Characteristic	Symbol	Condition	Min	Мах	Unit	Notes
Input current	I _{IN}	$0 \ V \leq V_{IN} \leq OV_{DD}$		±5	μA	—

Note:

1. This specification applies when operating from 3.3 V supply.

6 DDR1 and DDR2 SDRAM

This section describes the DC and AC electrical specifications for the DDR1 and DDR2 SDRAM interface of the MPC8323E. Note that DDR1 SDRAM is $Dn_GV_{DD}(typ) = 2.5$ V and DDR2 SDRAM is $Dn_GV_{DD}(typ) = 1.8$ V. The AC electrical specifications are the same for DDR1 and DDR2 SDRAM.

6.1 DDR1 and DDR2 SDRAM DC Electrical Characteristics

Table 12 provides the recommended operating conditions for the DDR2 SDRAM component(s) of the MPC8323E when $Dn_GV_{DD}(typ) = 1.8 \text{ V}$.

Parameter/Condition	Symbol	Min	Мах	Unit	Notes
I/O supply voltage	D <i>n_</i> GV _{DD}	1.71	1.89	V	1
I/O reference voltage	MVREF <i>n</i> REF	$0.49 \times Dn_GV_{DD}$	$0.51 \times Dn_GV_{DD}$	V	2
I/O termination voltage	V _{TT}	MVREFn _{REF} – 0.04	MVREF <i>n</i> _{REF} + 0.04	V	3
Input high voltage	V _{IH}	MVREFn _{REF} + 0.125	D <i>n_</i> GV _{DD} + 0.3	V	—
Input low voltage	V _{IL}	-0.3	MVREFn _{REF} – 0.125	V	—
Output leakage current	I _{OZ}	-9.9	9.9	μA	4
Output high current (V _{OUT} = 1.35 V)	I _{ОН}	-13.4	—	mA	—
Output low current (V _{OUT} = 0.280 V)	I _{OL}	13.4	—	mA	—

Table 12. DDR2 SDRAM DC Electrical Characteristics for Dn_GV_{DD}(typ) = 1.8 V

Notes:

1. Dn_GV_{DD} is expected to be within 50 mV of the DRAM Dn_GV_{DD} at all times.

- 2. MVREF n_{REF} is expected to be equal to $0.5 \times Dn_{\text{GV}_{\text{DD}}}$, and to track $Dn_{\text{GV}_{\text{DD}}}$ DC variations as measured at the receiver. Peak-to-peak noise on MVREF n_{REF} may not exceed ±2% of the DC value.
- 3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to MVREF*n*_{REF}. This rail should track variations in the DC level of MVREF*n*_{REF}.

4. Output leakage is measured with all outputs disabled, 0 V \leq V_{OUT} \leq Dn_GV_{DD}.

Table 13 provides the DDR2 capacitance when $Dn_GV_{DD}(typ) = 1.8$ V.

Table 13. DDR2 SDRAM Capacitance for Dn_GV_{DD}(typ) = 1.8 V

Parameter/Condition	Symbol	Min	Мах	Unit	Notes
Input/output capacitance: DQ, DQS	C _{IO}	6	8	pF	1



6.2 DDR1 and DDR2 SDRAM AC Electrical Characteristics

This section provides the AC electrical characteristics for the DDR1 and DDR2 SDRAM interface.

6.2.1 DDR1 and DDR2 SDRAM Input AC Timing Specifications

Table 16 provides the input AC timing specifications for the DDR2 SDRAM ($Dn_GV_{DD}(typ) = 1.8 \text{ V}$).

Table 16. DDR2 SDRAM Input AC Timing Specifications for 1.8-V Interface

At recommended operating conditions with Dn_GV_{DD} of 1.8 ± 5%.

Parameter	Symbol	Min	Мах	Unit	Notes
AC input low voltage	V _{IL}	—	MVREF <i>n</i> _{REF} – 0.25	V	—
AC input high voltage	V _{IH}	MVREFn _{REF} + 0.25	_	V	

Table 17 provides the input AC timing specifications for the DDR1 SDRAM ($Dn_GV_{DD}(typ) = 2.5 V$).

Table 17. DDR1 SDRAM Input AC Timing Specifications for 2.5 V Interface

At recommended operating conditions with Dn_GV_{DD} of 2.5 ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V _{IL}	—	MVREF <i>n</i> _{REF} – 0.31	V	-
AC input high voltage	V _{IH}	MVREF <i>n</i> _{REF} + 0.31	_	V	

Table 18 provides the input AC timing specifications for the DDR1 and DDR2 SDRAM interface.

Table 18. DDR1 and DDR2 SDRAM Input AC Timing Specifications

At recommended operating conditions with Dn_GV_{DD} of (1.8 or 2.5 V) ± 5%.

Parameter	Symbol	Min	Мах	Unit	Notes
Controller skew for MDQS—MDQ/MDM 266 MHz 200 MHz	^t CISKEW	-750 -1250	750 1250	ps	1, 2

Notes:

1. t_{CISKEW} represents the total amount of skew consumed by the controller between MDQS[n] and any corresponding bit that is captured with MDQS[n]. This should be subtracted from the total timing budget.

 The amount of skew that can be tolerated from MDQS to a corresponding MDQ signal is called t_{DISKEW}. This can be determined by the following equation: t_{DISKEW} = ±(T/4 – abs(t_{CISKEW})) where T is the clock period and abs(t_{CISKEW}) is the absolute value of t_{CISKEW}.



7 DUART

This section describes the DC and AC electrical specifications for the DUART interface of the MPC8323E.

7.1 DUART DC Electrical Characteristics

Table 20 provides the DC electrical characteristics for the DUART interface of the MPC8323E.

Table 20. DUART DC Electrical Characteristics

Parameter	Symbol	Min	Мах	Unit
High-level input voltage	V _{IH}	2	OV _{DD} + 0.3	V
Low-level input voltage OV _{DD}	V _{IL}	-0.3	0.8	V
High-level output voltage, $I_{OH} = -100 \ \mu A$	V _{OH}	OV _{DD} – 0.2	—	V
Low-level output voltage, $I_{OL} = 100 \ \mu A$	V _{OL}	—	0.2	V
Input current (0 V \leq V _{IN} \leq OV _{DD}) ¹	I _{IN}	—	±5	μA

Note:

1. Note that the symbol V_{IN} , in this case, represents the OV_{IN} symbol referenced in Table 1 and Table 2.

7.2 DUART AC Electrical Specifications

Table 21 provides the AC timing parameters for the DUART interface of the MPC8323E.

Table 21	. DUART	AC Timing	Specifications
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Parameter	Value	Unit	Notes
Minimum baud rate	256	baud	
Maximum baud rate	> 1,000,000	baud	1
Oversample rate	16		2

Notes:

1. Actual attainable baud rate is limited by the latency of interrupt processing.

2. The middle of a start bit is detected as the 8th sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16th sample.

8 Ethernet and MII Management

This section provides the AC and DC electrical characteristics for Ethernet and MII management.

8.1 Ethernet Controller (10/100 Mbps)—MII/RMII Electrical Characteristics

The electrical characteristics specified here apply to all MII (media independent interface) and RMII (reduced media independent interface), except MDIO (management data input/output) and MDC



Table 23. MII Transmit AC Timing Specifications (continued)

At recommended operating conditions with OV_{DD} of 3.3 V \pm 10%.

Parameter/Condition	Symbol ¹	Min	Typical	Max	Unit
TX_CLK data clock fall time	t _{MTXF}	1.0	_	4.0	ns

Note:

The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
</sub>

Figure 7 shows the MII transmit AC timing diagram.



Figure 7. MII Transmit AC Timing Diagram

8.2.1.2 MII Receive AC Timing Specifications

Table 24 provides the MII receive AC timing specifications.

Table 24. MII Receive AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol ¹	Min	Typical	Мах	Unit
RX_CLK clock period 10 Mbps	t _{MRX}	—	400	—	ns
RX_CLK clock period 100 Mbps	t _{MRX}	—	40	—	ns
RX_CLK duty cycle	t _{MRXH} /t _{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t _{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t _{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise time	t _{MRXR}	1.0	—	4.0	ns



8.2.2.1 RMII Transmit AC Timing Specifications

Table 23 provides the RMII transmit AC timing specifications.

Table 25. RMII Transmit AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol ¹	Min	Typical	Max	Unit
REF_CLK clock	t _{RMX}	_	20	_	ns
REF_CLK duty cycle	t _{RMXH} /t _{RMX}	35	_	65	%
REF_CLK to RMII data TXD[1:0], TX_EN delay	t _{RMTKHDX}	2	_	10	ns
REF_CLK data clock rise V _{IL} (min) to V _{IH} (max)	t _{RMXR}	1.0	_	4.0	ns
REF_CLK data clock fall $V_{IH}(max)$ to $V_{IL}(min)$	t _{RMXF}	1.0		4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of t_{(first three letters of functional block)(signal)(state)(reference)(state)} for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{RMTKHDX} symbolizes RMII transmit timing (RMT) for the time t_{RMX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{RMX} represents the RMII(RM) reference (X) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 10 shows the RMII transmit AC timing diagram.



Figure 10. RMII Transmit AC Timing Diagram

8.2.2.2 RMII Receive AC Timing Specifications

Table 24 provides the RMII receive AC timing specifications.

Table 26. RMII Receive AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol ¹	Min	Typical	Мах	Unit
REF_CLK clock period	t _{RMX}	—	20	—	ns
REF_CLK duty cycle	t _{RMXH} /t _{RMX}	35	—	65	%
RXD[1:0], CRS_DV, RX_ER setup time to REF_CLK	t _{RMRDVKH}	4.0	—	—	ns
RXD[1:0], CRS_DV, RX_ER hold time to REF_CLK	t _{RMRDXKH}	2.0	—	—	ns
REF_CLK clock rise VIL(min) to VIH(max)	t _{RMXR}	1.0	—	4.0	ns



Ethernet and MII Management

Table 26. RMII Receive AC Timing Specifications (continued)

At recommended operating conditions with OV_{DD} of 3.3 V \pm 10%.

Parameter/Condition	Symbol ¹	Min	Typical	Мах	Unit
REF_CLK clock fall time $V_{IH}(max)$ to $V_{IL}(min)$	t _{RMXF}	1.0		4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of t_{(first three letters of functional block)(signal)(state)(reference)(state)(signal)(state) for outputs. For example, t_{RMRDVKH} symbolizes RMII receive timing (RMR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{RMX} clock reference (K) going to the high (H) state or setup time. Also, t_{RMRDXKL} symbolizes RMII receive timing (RMR) with respect to the tinvalid (X) relative to the t_{RMX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{RMX} represents the RMII (RM) reference (X) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).}

Figure 11 provides the AC test load.



Figure 11. AC Test Load

Figure 12 shows the RMII receive AC timing diagram.



Figure 12. RMII Receive AC Timing Diagram

8.3 Ethernet Management Interface Electrical Characteristics

The electrical characteristics specified here apply to MII management interface signals MDIO (management data input/output) and MDC (management data clock). The electrical characteristics for MII, and RMII are specified in Section 8.1, "Ethernet Controller (10/100 Mbps)—MII/RMII Electrical Characteristics."



Parameter	Symbol ¹	Min	Мах	Unit	Notes
LALE output fall to LAD output transition (LATCH hold time)	t _{LBOTOT2}	3	_	ns	6
LALE output fall to LAD output transition (LATCH hold time)	t _{LBOTOT3}	2.5	_	ns	7
Local bus clock (LCLKn) to output valid	t _{LBKHOV}	—	3	ns	3
Local bus clock (LCLKn) to output high impedance for LAD/LDP	t _{LBKHOZ}	—	4	ns	8
Local bus clock (LCLKn) duty cycle	t _{LBDC}	47	53	%	_
Local bus clock (LCLKn) jitter specification	t _{LBRJ}	—	400	ps	_
Delay between the input clock (PCI_SYNC_IN) of local bus output clock (LCLK <i>n</i>)	t _{LBCDL}	—	1.7	ns	_

Table 30. Local Bus General Timing Parameters (continued)

Notes:

The symbols used for timing specifications follow the pattern of t_{(first two letters of functional block)(signal)(state)(reference)(state)} for inputs and t_(first two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t_{LBIXKH1} symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1).

2. All timings are in reference to falling edge of LCLK0 (for all outputs and for LGTA and LUPWAIT inputs) or rising edge of LCLK0 (for all other inputs).

All signals are measured from OV_{DD}/2 of the rising/falling edge of LCLK0 to 0.4 × OV_{DD} of the signal in question for 3.3-V signaling levels.

4. Input timings are measured at the pin.

5. t_{LBOTOT1} should be used when RCWH[LALE] is not set and the load on LALE output pin is at least 10 pF less than the load on LAD output pins.

 t_{LBOTOT2} should be used when RCWH[LALE] is set and the load on LALE output pin is at least 10 pF less than the load on LAD output pins.

7. t_{LBOTOT3} should be used when RCWH[LALE] is set and the load on LALE output pin equals to the load on LAD output pins.

8. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

Figure 14 provides the AC test load for the local bus.



Figure 14. Local Bus C Test Load



Figure 21 provides the boundary-scan timing diagram.



Figure 21. Boundary-Scan Timing Diagram





Figure 22. Test Access Port Timing Diagram



Figure 29 provides the AC test load for the GPIO.



15 IPIC

This section describes the DC and AC electrical specifications for the external interrupt pins of the MPC8323E.

15.1 IPIC DC Electrical Characteristics

Table 42 provides the DC electrical characteristics for the external interrupt pins of the MPC8323E.

Characteristic	Symbol	Condition	Min	Мах	Unit
Input high voltage	V _{IH}	—	2.0	OV _{DD} + 0.3	V
Input low voltage	V _{IL}	—	-0.3	0.8	V
Input current	I _{IN}	—	—	±5	μA
Output low voltage	V _{OL}	I _{OL} = 6.0 mA	_	0.5	V
Output low voltage	V _{OL}	I _{OL} = 3.2 mA	—	0.4	V

Table 42. IPIC DC Electrical Characteristics^{1,2}

Notes:

1. This table applies for pins IRQ[0:7], IRQ_OUT, MCP_OUT, and CE ports Interrupts.

2. IRQ_OUT and MCP_OUT are open drain pins, thus V_{OH} is not relevant for those pins.

15.2 IPIC AC Timing Specifications

Table 43 provides the IPIC input and output AC timing specifications.

Table 43. IPIC Input AC Timing Specifications¹

Characteristic	Symbol ²	Min	Unit
IPIC inputs—minimum pulse width	t _{PIWID}	20	ns

Notes:

1. Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of CLKIN. Timings are measured at the pin.

IPIC inputs and outputs are asynchronous to any visible clock. IPIC outputs should be synchronized before use by any
external synchronous logic. IPIC inputs are required to be valid for at least t_{PIWID} ns to ensure proper operation when working
in edge triggered mode.



SPI

16 SPI

This section describes the DC and AC electrical specifications for the SPI of the MPC8323E.

16.1 SPI DC Electrical Characteristics

Table 44 provides the DC electrical characteristics for the MPC8323E SPI.

Characteristic	Symbol	Condition	Min	Мах	Unit
Output high voltage	V _{OH}	I _{OH} = -6.0 mA	2.4	—	V
Output low voltage	V _{OL}	I _{OL} = 6.0 mA	—	0.5	V
Output low voltage	V _{OL}	I _{OL} = 3.2 mA	—	0.4	V
Input high voltage	V _{IH}	—	2.0	OV _{DD} + 0.3	V
Input low voltage	V _{IL}	—	-0.3	0.8	V
Input current	I _{IN}	$0 \ V \le V_{IN} \le OV_{DD}$	—	±5	μA

Table 44. SPI DC Electrical Characteristics

16.2 SPI AC Timing Specifications

Table 45 and provide the SPI input and output AC timing specifications.

Table 45. SPI AC Timing Specifications¹

Characteristic	Symbol ²	Min	Мах	Unit
SPI outputs—Master mode (internal clock) delay	t _{NIKHOV}	0.5	6	ns
SPI outputs—Slave mode (external clock) delay	t _{NEKHOV}	2	8	ns
SPI inputs—Master mode (internal clock) input setup time	t _{NIIVKH}	6	—	ns
SPI inputs—Master mode (internal clock) input hold time	t _{NIIXKH}	0	—	ns
SPI inputs—Slave mode (external clock) input setup time	t _{NEIVKH}	4	—	ns
SPI inputs—Slave mode (external clock) input hold time	t _{NEIXKH}	2	—	ns

Notes:

1. Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.

The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t<sub>(first two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t_{NIKHOV} symbolizes the NMSI outputs internal timing (NI) for the time t_{SPI} memory clock reference (K) goes from the high state (H) until outputs (O) are valid (V).
</sub></sub>

Figure 30 provides the AC test load for the SPI.



Figure 30. SPI AC Test Load



USB

20 USB

This section provides the AC and DC electrical specifications for the USB interface of the MPC8323E.

20.1 USB DC Electrical Characteristics

Table 53 provides the DC electrical characteristics for the USB interface.

Table 53. USB DC Electrical Characteristics¹

Parameter	Symbol	Min	Мах	Unit
High-level input voltage	V _{IH}	2	OV _{DD} + 0.3	V
Low-level input voltage	V _{IL}	-0.3	0.8	V
High-level output voltage, $I_{OH} = -100 \ \mu A$	V _{OH}	OV _{DD} – 0.2	—	V
Low-level output voltage, $I_{OL} = 100 \ \mu A$	V _{OL}	—	0.2	V
Input current	I _{IN}	-	±5	μA

Note:

1. Note that the symbol V_{IN} , in this case, represents the OV_{IN} symbol referenced in Table 1 and Table 2.

20.2 USB AC Electrical Specifications

Table 54 describes the general timing parameters of the USB interface of the MPC8323E.

Table 54. 03D General Tilling Parameters	Table 54.	USB	General	Timing	Parameters
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Parameter	Symbol ¹	Min	Мах	Unit	Notes
USB clock cycle time	t _{USCK}	20.83	—	ns	Full speed 48 MHz
USB clock cycle time	t _{USCK}	166.67	—	ns	Low speed 6 MHz
Skew between TXP and TXN	t _{USTSPN}	_	5	ns	—
Skew among RXP, RXN, and RXD	t _{USRSPND}	_	10	ns	Full speed transitions
Skew among RXP, RXN, and RXD	tUSRPND		100	ns	Low speed transitions

Notes:

 The symbols used for timing specifications follow the pattern of t_{(first two letters of functional block)(state)(signal)} for receive signals and t_{(first two letters of functional block)(state)(signal)} for transmit signals. For example, t_{USRSPND} symbolizes USB timing (US) for the USB receive signals skew (RS) among RXP, RXN, and RXD (PND). Also, t_{USTSPN} symbolizes USB timing (US) for the USB transmit signals skew (TS) between TXP and TXN (PN).

2. Skew measurements are done at $OV_{DD}/2$ of the rising or falling edge of the signals.

Figure 41 provide the AC test load for the USB.



Figure 41. USB AC Test Load



This section details package parameters, pin assignments, and dimensions. The MPC8323E is available in a thermally enhanced Plastic Ball Grid Array (PBGA); see Section 21.1, "Package Parameters for the MPC8323E PBGA," and Section 21.2, "Mechanical Dimensions of the MPC8323E PBGA," for information on the PBGA.

21.1 Package Parameters for the MPC8323E PBGA

The package parameters are as provided in the following list. The package type is $27 \text{ mm} \times 27 \text{ mm}$, 516 PBGA.

Package outline	$27 \text{ mm} \times 27 \text{ mm}$
Interconnects	516
Pitch	1.00 mm
Module height (typical)	2.25 mm
Solder Balls	62 Sn/36 Pb/2 Ag (ZQ package) 95.5 Sn/0.5 Cu/4Ag (VR package)
Ball diameter (typical)	0.6 mm

21.2 Mechanical Dimensions of the MPC8323E PBGA

Figure 42 shows the mechanical dimensions and bottom surface nomenclature of the MPC8323E, 516-PBGA package.





Notes:

1.All dimensions are in millimeters.

2.Dimensions and tolerances per ASME Y14.5M-1994.

3.Maximum solder ball diameter measured parallel to datum A.

4.Datum A, the seating plane, is determined by the spherical crowns of the solder balls.

Figure 42. Mechanical Dimensions and Bottom Surface Nomenclature of the MPC8323E PBGA



Signal	Package Pin Number	Pin Type	Power Supply	Notes
MEMC_MDQ29	AD20	10	GV _{DD}	
MEMC_MDQ30	AF23	10	GV _{DD}	
MEMC_MDQ31	AD22	IO	GV _{DD}	—
MEMC_MDM0	AC9	0	GV _{DD}	—
MEMC_MDM1	AD5	0	GV _{DD}	—
MEMC_MDM2	AE20	0	GV _{DD}	—
MEMC_MDM3	AE22	0	GV _{DD}	—
MEMC_MDQS0	AE8	IO	GV _{DD}	—
MEMC_MDQS1	AE5	IO	GV _{DD}	—
MEMC_MDQS2	AC19	IO	GV _{DD}	—
MEMC_MDQS3	AE23	IO	GV _{DD}	—
MEMC_MBA0	AD16	0	GV _{DD}	—
MEMC_MBA1	AD17	0	GV _{DD}	—
MEMC_MBA2	AE17	0	GV _{DD}	—
MEMC_MA0	AD12	0	GV _{DD}	—
MEMC_MA1	AE12	0	GV _{DD}	—
MEMC_MA2	AF12	0	GV _{DD}	—
MEMC_MA3	AC13	0	GV _{DD}	—
MEMC_MA4	AD13	0	GV _{DD}	—
MEMC_MA5	AE13	0	GV _{DD}	—
MEMC_MA6	AF13	0	GV _{DD}	—
MEMC_MA7	AC15	0	GV _{DD}	—
MEMC_MA8	AD15	0	GV _{DD}	—
MEMC_MA9	AE15	0	GV _{DD}	—
MEMC_MA10	AF15	0	GV _{DD}	—
MEMC_MA11	AE16	0	GV _{DD}	—
MEMC_MA12	AF16	0	GV _{DD}	—
MEMC_MA13	AB16	0	GV _{DD}	—
MEMC_MWE	AC17	0	GV _{DD}	—
MEMC_MRAS	AE11	0	GV _{DD}	[_
MEMC_MCAS	AD11	0	GV _{DD}	[_
MEMC_MCS	AC11	0	GV _{DD}	_

Table 55. MPC8323E PBGA Pinout Listing (continued)



Table 55. MPC8323E PBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
GPIO_PB17/BRGO1/CE_EXT_REQ1	D10	IO	OV _{DD}	
GPIO_PB18/Enet4_TXD[0]/SER4_TXD[0]/ TDMD_TXD[0]	C10	IO	OV _{DD}	—
GPIO_PB19/Enet4_TXD[1]/SER4_TXD[1]/ TDMD_TXD[1]	C9	IO	OV _{DD}	—
GPIO_PB20/Enet4_TXD[2]/SER4_TXD[2]/ TDMD_TXD[2]	D8	IO	OV _{DD}	—
GPIO_PB21/Enet4_TXD[3]/SER4_TXD[3]/ TDMD_TXD[3]	C8	IO	OV _{DD}	—
GPIO_PB22/Enet4_RXD[0]/SER4_RXD[0]/ TDMD_RXD[0]	C15	IO	OV _{DD}	—
GPIO_PB23/Enet4_RXD[1]/SER4_RXD[1]/ TDMD_RXD[1]	C14	Ю	OV _{DD}	—
GPIO_PB24/Enet4_RXD[2]/SER4_RXD[2]/ TDMD_RXD[2]	D13	IO	OV _{DD}	—
GPIO_PB25/Enet4_RXD[3]/SER4_RXD[3]/ TDMD_RXD[3]	C13	IO	OV _{DD}	—
GPIO_PB26/Enet4_RX_ER/SER4_CD/TDMD_REQ	C12	IO	OV _{DD}	
GPIO_PB27/Enet4_TX_ER/TDMD_CLKO	D11	IO	OV _{DD}	
GPIO_PB28/Enet4_RX_DV/SER4_CTS/ TDMD_RSYNC	D12	IO	OV _{DD}	—
GPIO_PB29/Enet4_COL/RXD[4]/SER4_RXD[4]/ TDMD_STROBE	D7	IO	OV _{DD}	_
GPIO_PB30/Enet4_TX_EN/SER4_RTS/ TDMD_TSYNC	C11	IO	OV _{DD}	—
GPIO_PB31/Enet4_CRS/SDET	C7	IO	OV _{DD}	_
GPIO_PC0/UPC1_TxDATA[0]/SER5_TXD[0]	A18	Ю	OV_{DD}	_
GPIO_PC1/UPC1_TxDATA[1]/SER5_TXD[1]	A19	Ю	OV_{DD}	_
GPIO_PC2/UPC1_TxDATA[2]/SER5_TXD[2]	B18	Ю	OV _{DD}	—
GPIO_PC3/UPC1_TxDATA[3]/SER5_TXD[3]	B19	Ю	OV _{DD}	_
GPIO_PC4/UPC1_TxDATA[4]	A24	Ю	OV_{DD}	_
GPIO_PC5/UPC1_TxDATA[5]	B24	Ю	OV _{DD}	—
GPIO_PC6/UPC1_TxDATA[6]	A23	Ю	OV_{DD}	_
GPIO_PC7/UPC1_TxDATA[7]	B26	IO	OV _{DD}	
GPIO_PC8/UPC1_RxDATA[0]/SER5_RXD[0]	A21	IO	OV _{DD}	—
GPIO_PC9/UPC1_RxDATA[1]/SER5_RXD[1]	B20	IO	OV _{DD}	



Characteristic ¹	Max Operating Frequency	Unit
DDR1/DDR2 memory bus frequency (MCLK) ²	133	MHz
Local bus frequency (LCLKn) ³	66	MHz
PCI input frequency (CLKIN or PCI_CLK)	66	MHz

Table 57. Operating Frequencies for PBGA (continued)

¹ The CLKIN frequency, RCWL[SPMF], and RCWL[COREPLL] settings must be chosen such that the resulting *csb_clk*, MCLK, LCLK[0:2], and *core_clk* frequencies do not exceed their respective maximum or minimum operating frequencies.

² The DDR1/DDR2 data rate is 2× the DDR1/DDR2 memory bus frequency.

³ The local bus frequency is 1/2, 1/4, or 1/8 of the *lb_clk* frequency (depending on LCRR[CLKDIV]) which is in turn 1× or 2× the *csb_clk* frequency (depending on RCWL[LBCM]).

22.4 System PLL Configuration

The system PLL is controlled by the RCWL[SPMF] parameter. Table 58 shows the multiplication factor encodings for the system PLL.

NOTE

System PLL VCO frequency = $2 \times (CSB \text{ frequency}) \times (System PLL VCO divider})$.

The VCO divider needs to be set properly so that the System PLL VCO frequency is in the range of 300–600 MHz.

RCWL[SPMF]	System PLL Multiplication Factor
0000	Reserved
0001	Reserved
0010	× 2
0011	× 3
0100	× 4
0101	× 5
0110	× 6
0111-1111	Reserved

Table 58. System PLL Multiplication Factors

As described in Section 22, "Clocking," the LBCM, DDRCM, and SPMF parameters in the reset configuration word low and the CFG_CLKIN_DIV configuration input signal select the ratio between the primary clock input (CLKIN or PCI_CLK) and the internal coherent system bus clock (*csb_clk*). Table 59



Clocking

shows the expected frequency values for the CSB frequency for select *csb_clk* to CLKIN/PCI_SYNC_IN ratios.

		csh clk:	Input Clock Frequency (MHz)		
CFG_CLKIN_DIV_B at Reset ¹	SPMF	Input Clock	25	33.33	66.67
		Ratio	csb_cll	<i>csb_clk</i> Frequency (MH	
High	0010	2:1			133
High	0011	3:1		100	
High	0100	4 : 1	100	133	
High	0101	5:1	125		
High	0110	6:1			
High	0111	7:1			
High	1000	8:1			
High	1001	9:1			
High	1010	10 : 1			
High	1011	11 : 1			
High	1100	12 : 1			
High	1101	13 : 1			
High	1110	14 : 1			
High	1111	15 : 1			
High	0000	16 : 1			
Low	0010	2 : 1			133
Low	0011	3:1		100	
Low	0100	4 : 1		133	
Low	0101	5 : 1			
Low	0110	6:1			
Low	0111	7:1			
Low	1000	8:1			
Low	1001	9:1			
Low	1010	10 : 1			
Low	1011	11:1			
Low	1100	12 : 1			
Low	1101	13 : 1			
Low	1110	14 : 1			
Low	1111	15 : 1			
Low	0000	16 : 1			

Table 59. CSB Frequency Options

¹ CFG_CLKIN_DIV_B is only used for host mode; CLKIN must be tied low and

CFG_CLKIN_DIV_B must be pulled up (high) in agent mode.

² CLKIN is the input clock in host mode; PCI_CLK is the input clock in agent mode.



Clocking

22.6 QUICC Engine PLL Configuration

The QUICC Engine PLL is controlled by the RCWL[CEPMF] and RCWL[CEPDF] parameters. Table 61 shows the multiplication factor encodings for the QUICC Engine PLL.

RCWL[CEPMF]	RCWL[CEPDF]	QUICC Engine PLL Multiplication Factor = RCWL[CEPMF]/ (1 + RCWL[CEPDF)
00000-00001	0	Reserved
00010	0	× 2
00011	0	× 3
00100	0	× 4
00101	0	× 5
00110	0	× 6
00111	0	× 7
01000	0	× 8
01001–11111	0	Reserved

Table 61. QUICC Engine PLL Multiplication Factors

The RCWL[CEVCOD] denotes the QUICC Engine PLL VCO internal frequency as shown in Table 62.

Table 62. QUICC Engine PLL VCO Divider

RCWL[CEVCOD]	VCO Divider
00	4
01	8
10	2
11	Reserved

NOTE

The VCO divider (RCWL[CEVCOD]) must be set properly so that the QUICC Engine VCO frequency is in the range of 300–600 MHz. The QUICC Engine frequency is not restricted by the CSB and core frequencies. The CSB, core, and QUICC Engine frequencies should be selected according to the performance requirements.

The QUICC Engine VCO frequency is derived from the following equations:

 $ce_clk = (\text{primary clock input} \times \text{CEPMF}) \div (1 + \text{CEPDF})$

QUICC Engine VCO Frequency = $ce_clk \times VCO$ divider $\times (1 + CEPDF)$